

**Notice of References Cited**

Applicant/Patent

Shepard

Application/Control No.

09/453,319

Examiner

Gall Verbitsky

Art Unit

2859

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**U.S. PATENT DOCUMENTS**

	<b>Document Number</b> Country Code-Number-Kind Code	<b>Date</b> MM-YYYY <sup>1</sup>	<b>Name</b>	<b>Classification<sup>2</sup></b>	
A	6286206B1	09.11.01	Li	29	840
B					
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**FOREIGN PATENT DOCUMENTS**

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**NON-PATENT DOCUMENTS**

	<b>Include, as applicable: Author, Title, Date, Publisher, Edition or Volume, Pertinent Pages</b>				
U	H.I. McHenry. A Compliance Method for Crack Growth Studies at Elevated Temperature. Journal of Materials, JMLSA, Vol. 6, No. 4, pages 862-873. Dec. 1971				
V					
W					
X					

<sup>\*</sup> A copy of this reference is not being furnished with this Office action. See MPEP § 707.05(a).<sup>1</sup> Dates in MM-YYYY format are publication dates.<sup>2</sup> Classifications may be U.S. or foreign.